

## WEST Search History





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<input type="checkbox"/>	L17	L16 same (fail\$4 or fault or error)	14
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<input type="checkbox"/>	L14	fault with event with (notif\$9 or respon\$7)	812
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<input type="checkbox"/>	L11	(event near2 policy)	217
<input type="checkbox"/>	L10	(default near5 (event near2 policy))	0
<input type="checkbox"/>	L9	(default near2 event near2 policy)	0
<input type="checkbox"/>	L8	L3 and (default with response with event)	2
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